Manufacturability of Electronic Chips¹

Rakesh R. Vallishayee and Steven A. Orszag Princeton University, Princeton, NJ 08544, USA

Eric Jackson Cambridge Hydrodynamics Inc., P.O.Box 1403 Princeton, NJ 08542, USA

Eytan Barouch Boston University, Boston, MA 02144, USA

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ABSTRACT

If the size of features on a microchip are of order of or smaller than the wavelength of the light used in their manufacture, manufacturability of the chip suffers due to diffraction. The degrading effect of diffraction can be handled by biasing masks used for patterning the chips and optimizing stepper parameters are designed and implemented. The algorithms are efficient and feasible for industrial size masks.

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